



Formation of Oxide Layers in Mildly Oxidizing Gas

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- Background
 - ESS tungsten target
 - Tungsten oxides and oxidation kinetics
- Materials and Methods
 - Samples, atmospheres & temperatures
 - Experimental set-up
- Results
 - Mass changes
 - Oxide layer thickness
 - Surface analysis

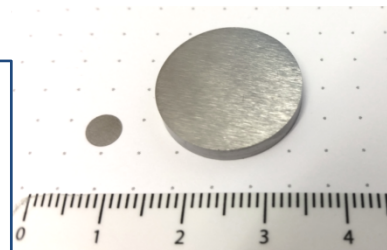
Target at ESS

- Tungsten heated during spallation
 - Max. temp $\sim 450^{\circ}\text{C}$
 - Helium cooling system
- O_2 and H_2O impurities in He
 - Causing oxidation \rightarrow Erosion of target?
 - Oxide vaporized $>750^{\circ}\text{C}$ \rightarrow Release of radioactive particles
- Information on oxidation at different oxygen partial pressures useful under normal and off-normal operating conditions

Understanding the oxidation behaviour of pure W in mildly oxidizing gas mixtures

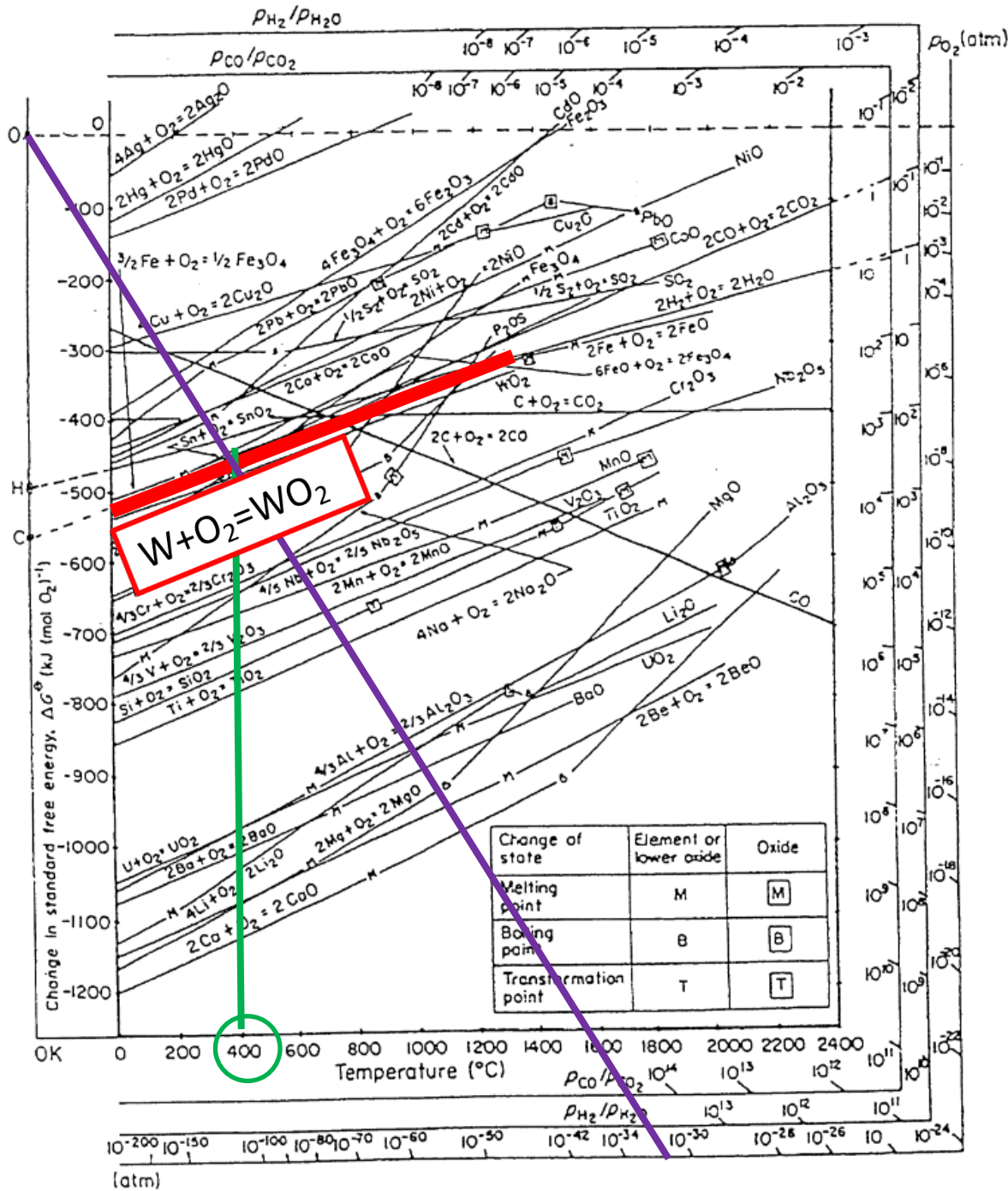
- Estimating the impact of impurities like O_2 and $H_2O(g)$ in He gas
- Study the formation of oxide layers on W in gas mixtures with different oxygen contents
 - 5%, 0.5% and 5ppm O_2
- Study the kinetics of oxidation and the nature of oxides formed
- Identify safe operation limits for target operation
 - Temperature, environment

E-polished, rolled W.
20mm dia, 3mm thick
5.5mm dia, 26 μm thick



Protective gas atmosphere

- Prevent/minimize the oxidation of tungsten
- Requirement: $(p_{O_2})_{He} < (p_{O_2})_{W-WO_{3-x} \text{ equilibrium}}$
- Monitoring the effective partial pressure of oxygen in the gas is crucial
- Purification of He gas to reduce O_2 and moisture levels



Ellingham diagram

$W + O_2 = WO_2$ at $400^\circ C$
 $\rightarrow p_{O_2} < 10^{-32}$ atm.

In order to keep W free from oxide

Tungsten oxidation process

The overall tungsten oxidation process can be divided into three different stages:

1. Phase boundary controlled

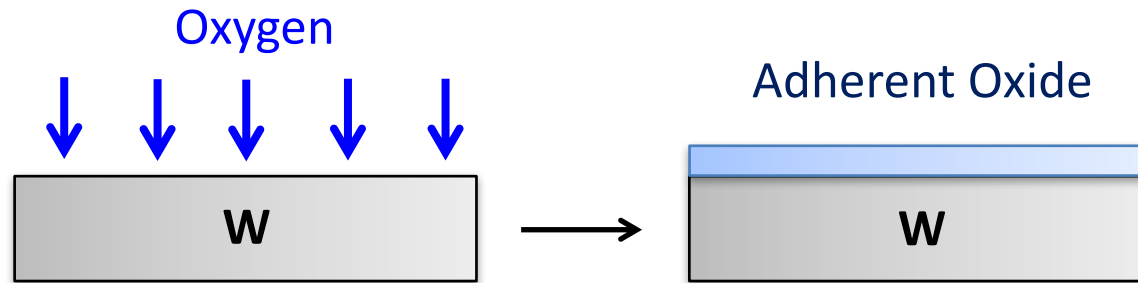
- Formation of first oxide layer

2. Diffusion controlled

- Growth of dark and protective layer
- Growth of porous WO_3

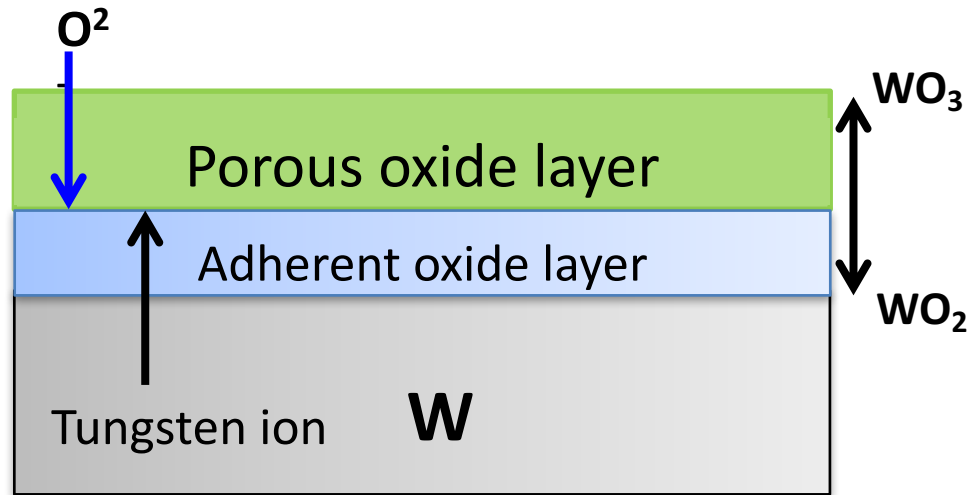
3. Sublimation of WO_3

Formation of oxide layer $> 600^{\circ}\text{C}$



- Initial oxidation is phase boundary controlled.
- This oxide layer is thin, adherent and protective.
- Rate is limited according to the rate of diffusion of O^{2-} ions through the oxide scale \rightarrow parabolic oxidation rate

Formation of tungsten oxides between 600°-750°C



- WO_3 forms on top of the first layer
- Porous, not very adhesive, volume ratio of 3.35 \rightarrow WO_3 creates high stresses, oxide layer cracks, exposes fresh metal surface.
- The non-protective nature of WO_3 results in a linear oxidation rate
- W/O ratio varies, lowest oxide closest to metal surface
- Sublimation takes place $<750^\circ C$
 - Conflicting data on threshold temp for sublimation in literature. Dependent on P_{O_2} and P_{H_2O}

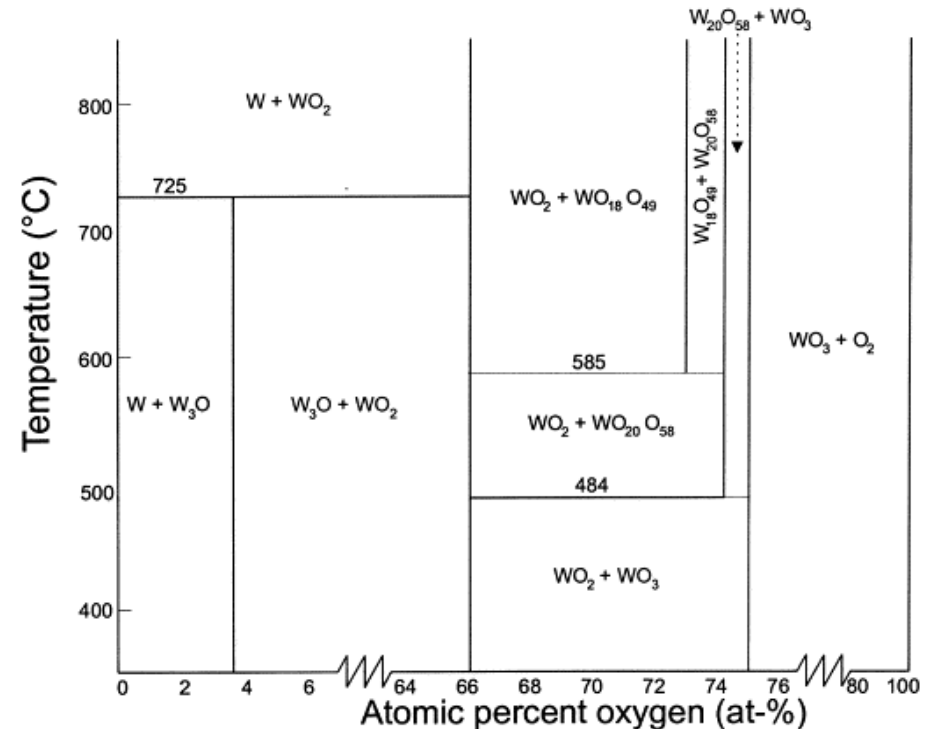
Tungsten in contact with H₂O



- Formation of some gaseous species contribute to the sublimation of tungsten oxides (above 750°C)
- The above reaction is pushed to the right as the product (tungstic acid) is formed and removed quickly.
- Green et. al, *Vaporization of tungsten in flowing steam at high temperatures* (2001):
 - 100% steam superheated to 140°C
 - Formation of $\text{WO}_3\text{H}_2\text{O}(\text{g})$ at as low as 800°C

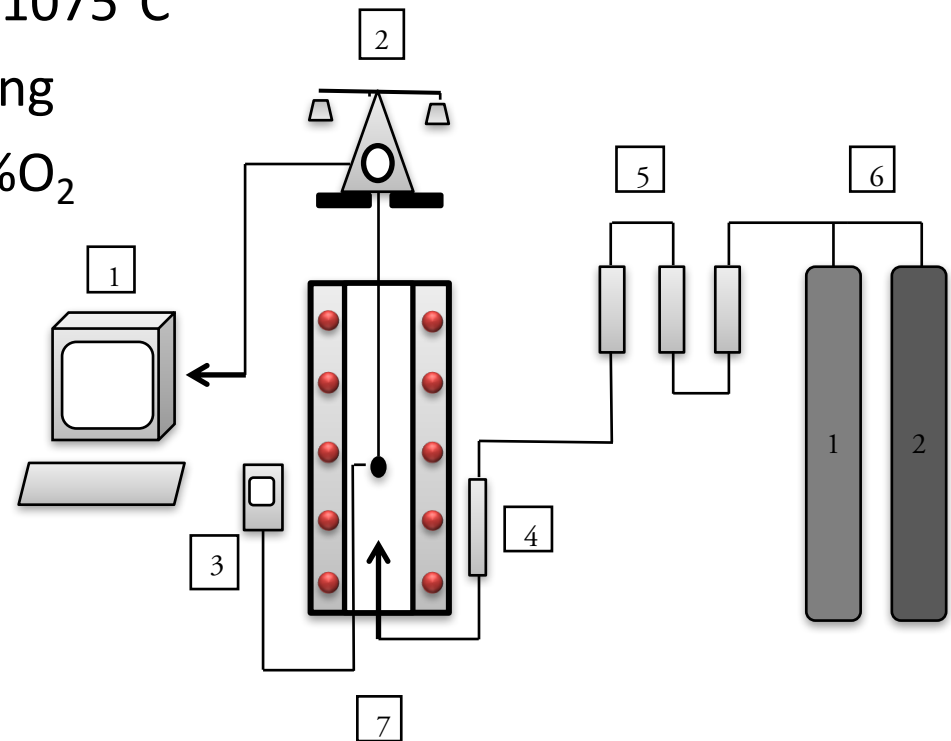
Various W oxides, W-O system

- Oxides with higher oxygen content are near the oxide-oxygen phase boundary
- The oxides most frequently mentioned are:
 - WO_2 , $WO_{2,72}$ ($W_{18}O_{49}$), $WO_{2,9}$ ($W_{20}O_{58}$) and WO_3
- Other oxides mentioned in the literature
 - ex. $WO_{2,75}$, $WO_{2,92}$ and $WO_{2,96}$



Experimental setup (TGA)

- Thermogravimetric analysis
 - Isothermal studies from 400°-1075°C
 - N₂ protective gas during heating
 - Reactant gas mixture of He-x%O₂ where x = 5ppm to 5%
 - 2h holding time



(1) Data acquisition, (2) Balance with suspended sample, (3) Thermocouple (4), Flow meter, (5) Drierite & calcium chloride, (6) Gas cylinders (7) Furnace

W-samples after oxidation in He+Ar+H₂O gas mixture (2h, $p_{H_2O} \sim 0.0078$ atm.)



400°C



500°C



600°C



700°C



750°C



800°C



900°C

W-samples after oxidation in He+0.5%O₂ gas mixture (2h, $p_{O_2} \sim 0.005$ atm.)



400°C



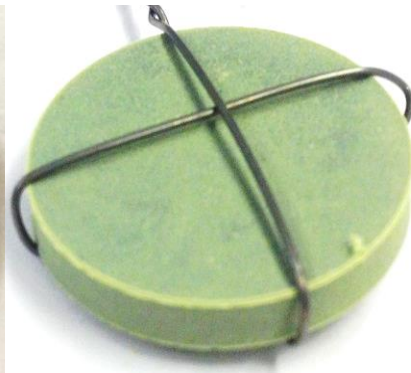
500°C



600°C



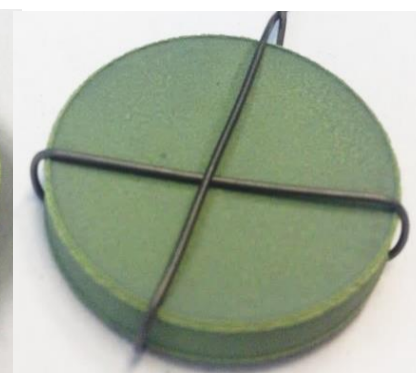
700°C



750°C

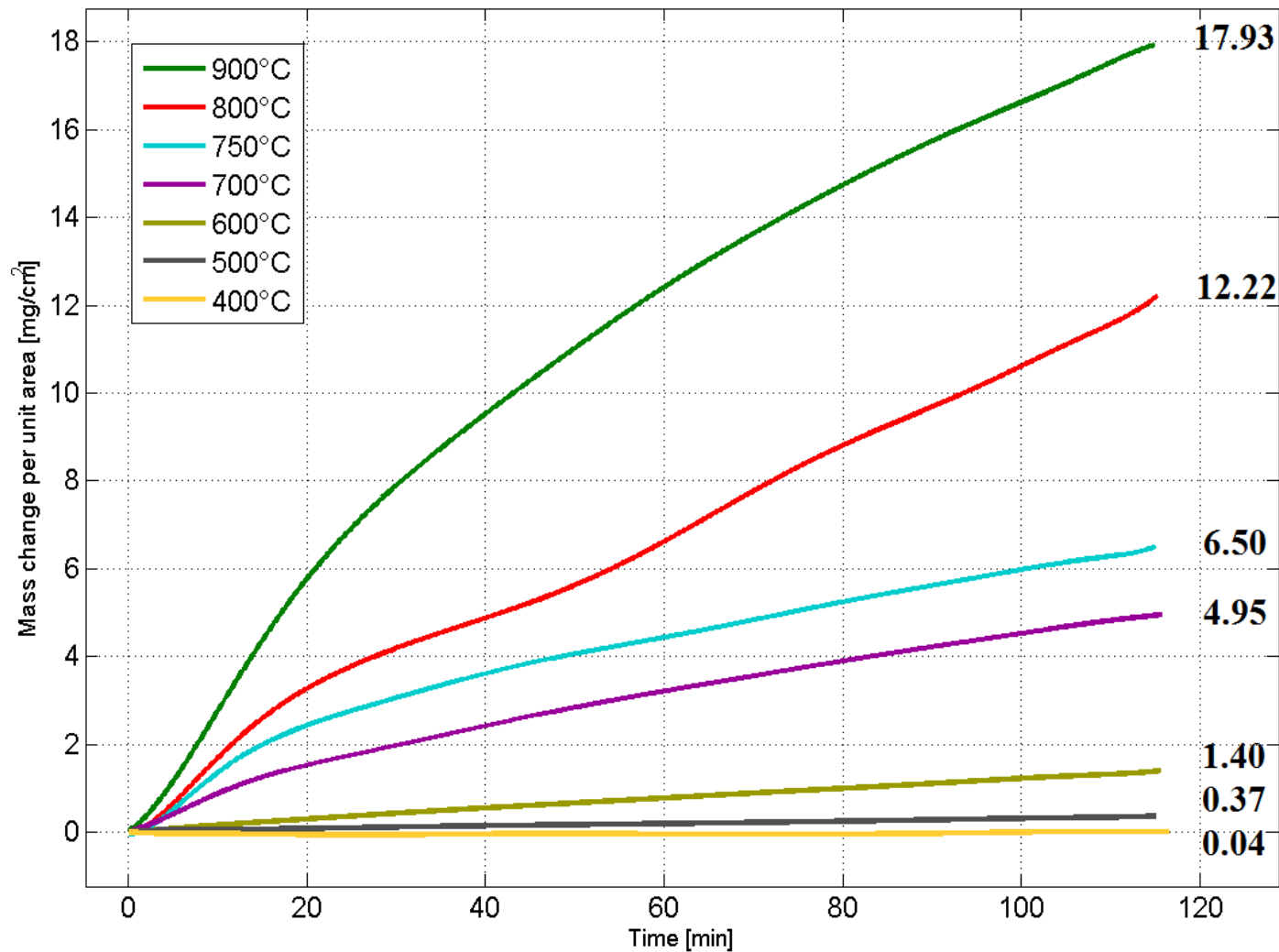


800°C

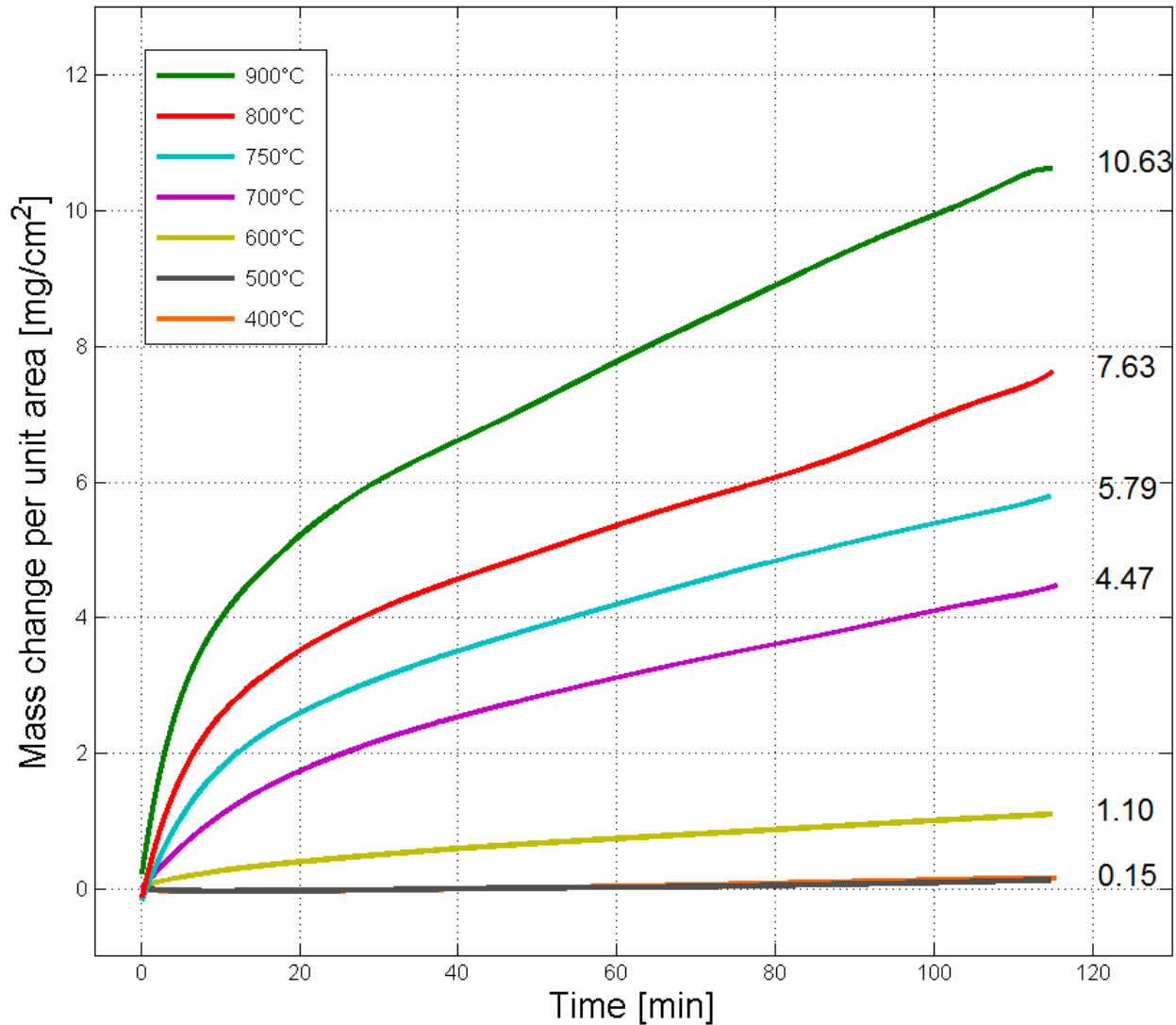


900°C

Tungsten in He+0.5%O₂ gas mixture (2h, $p_{O_2} \sim 0.005$ atm.)

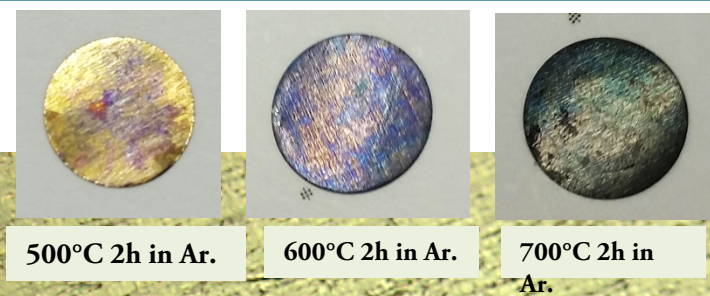


Tungsten in He+Ar+H₂O gas mixture (pH₂O= 7.8×10⁻³atm)



Results from STA ($p_{O_2} \sim 5 \cdot 10^{-6}$)

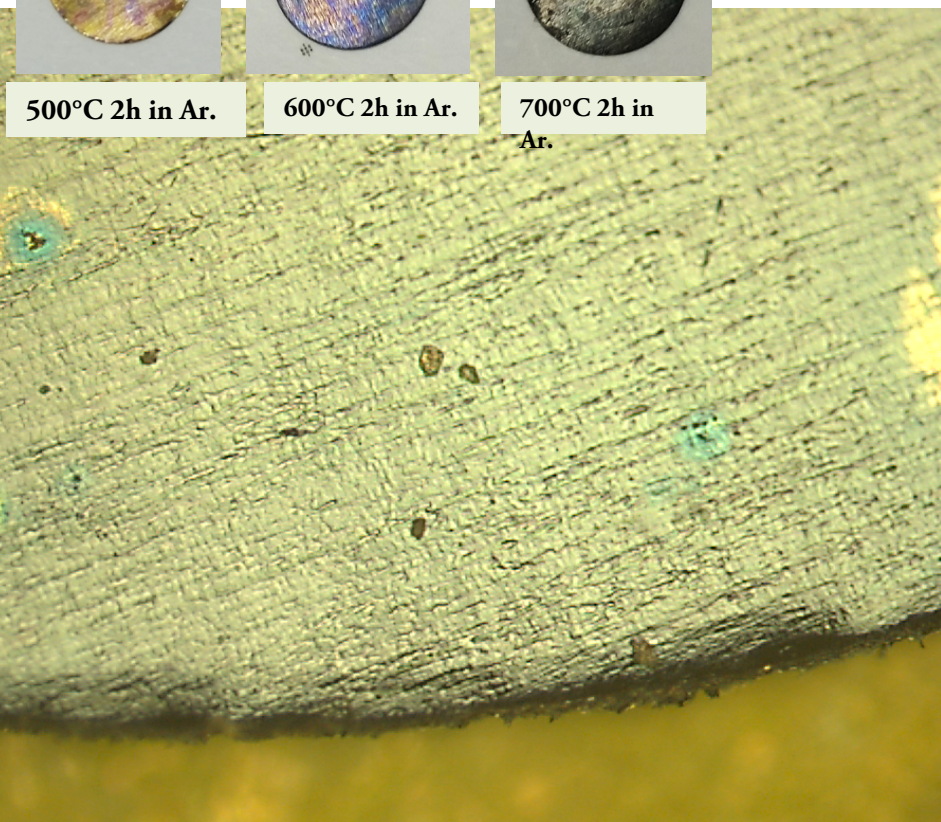
Foil in STA for 48h in pure Argon



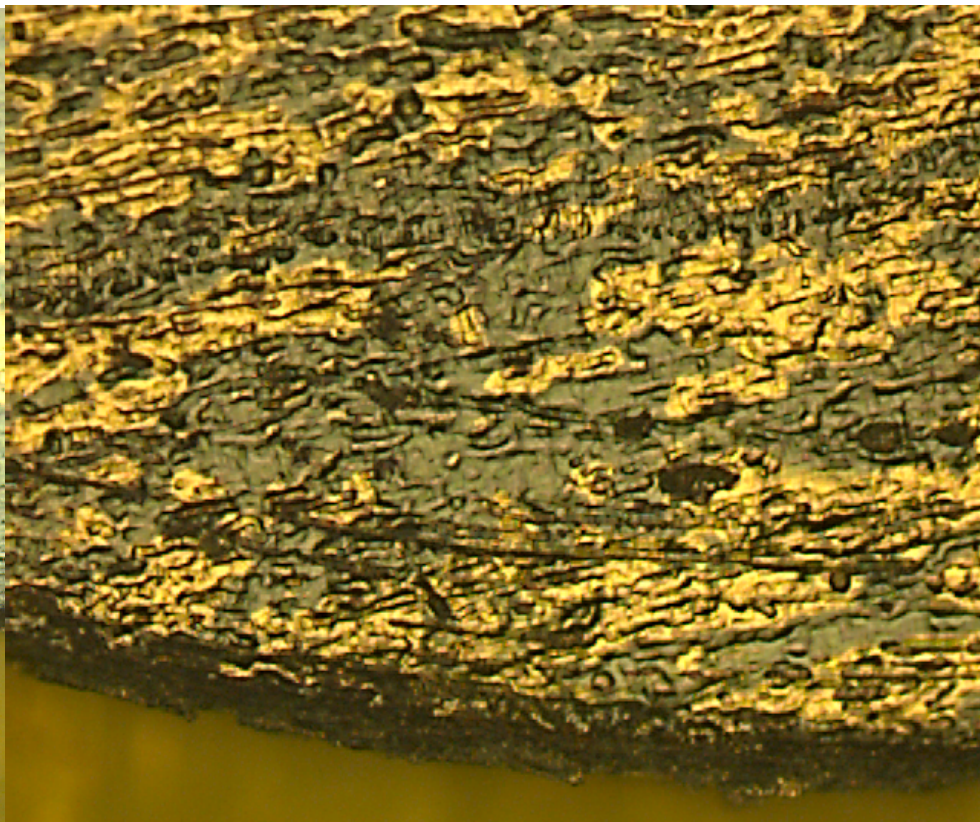
500°C 2h in Ar.

600°C 2h in Ar.

700°C 2h in Ar.



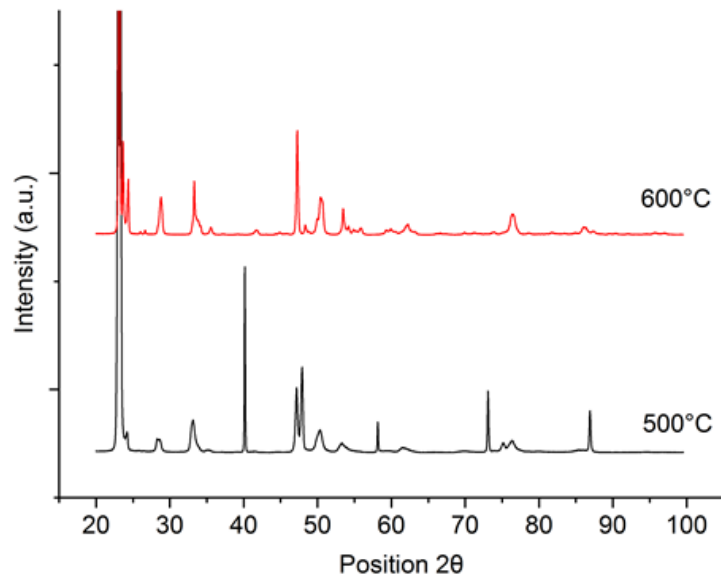
500°C



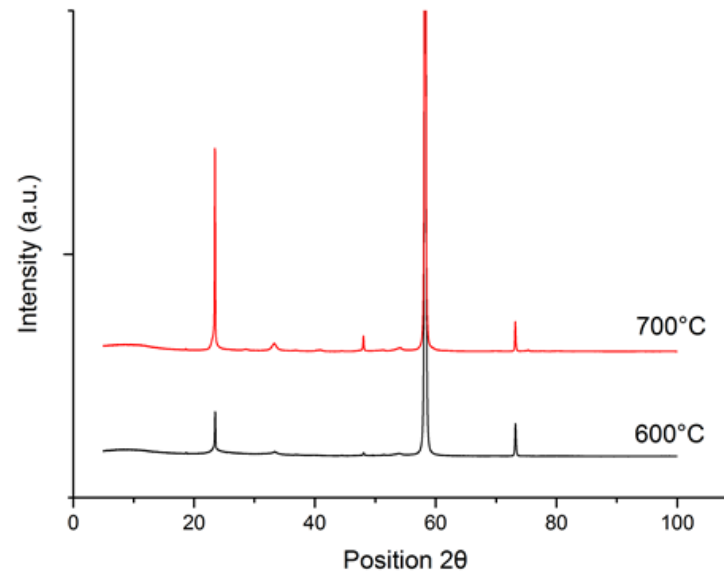
550°C

XRD measurements

W DISCS IN AIR, 24H



W FOILS IN ARGON, 2H



Results from the XRD measurements indicate the following oxides :

AIR		ARGON	
600°C	WO ₃	700°C	W ₁₀ O ₂₉
500°C	W ₁₈ O ₄₉	600°C	W ₁₈ O ₄₉ / W ₁₀ O ₂₉

Oxidized tungsten samples (He-5%O₂, 2h)

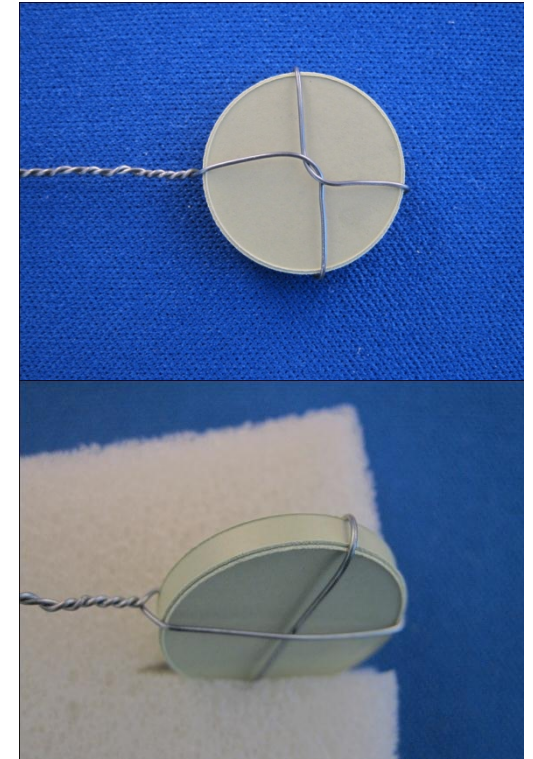
600°C



700°C

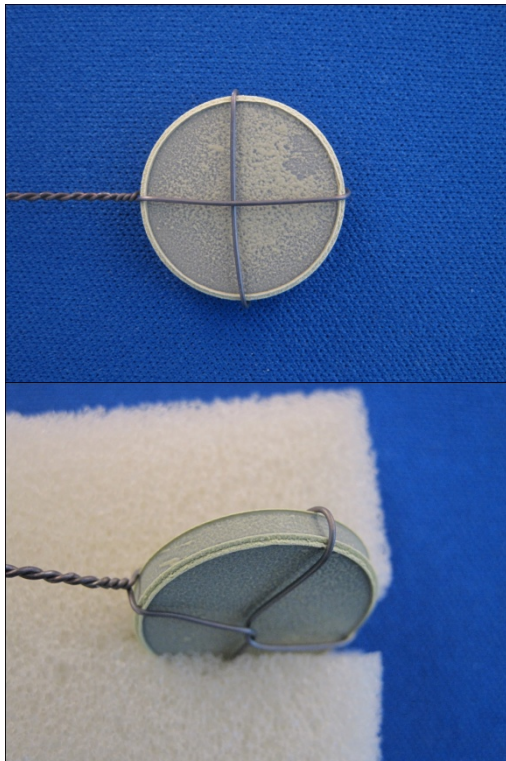


800°C



Oxidized tungsten samples (He-5%O₂, 2h)

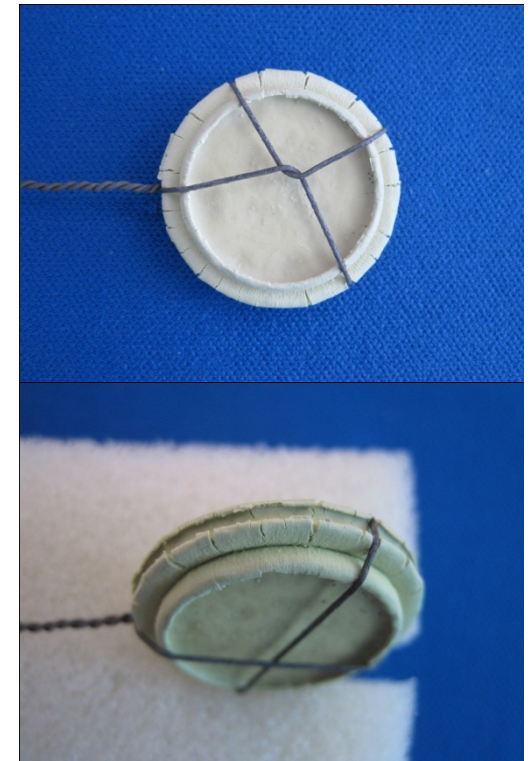
900°C



1000°C



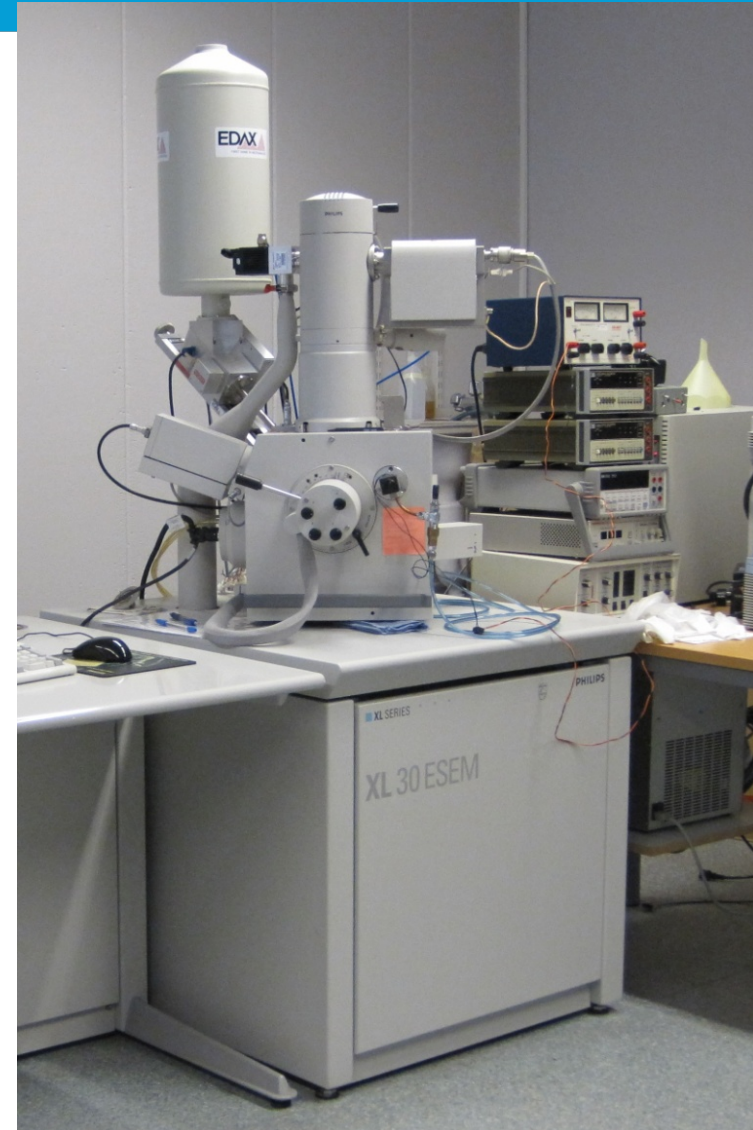
1075°C



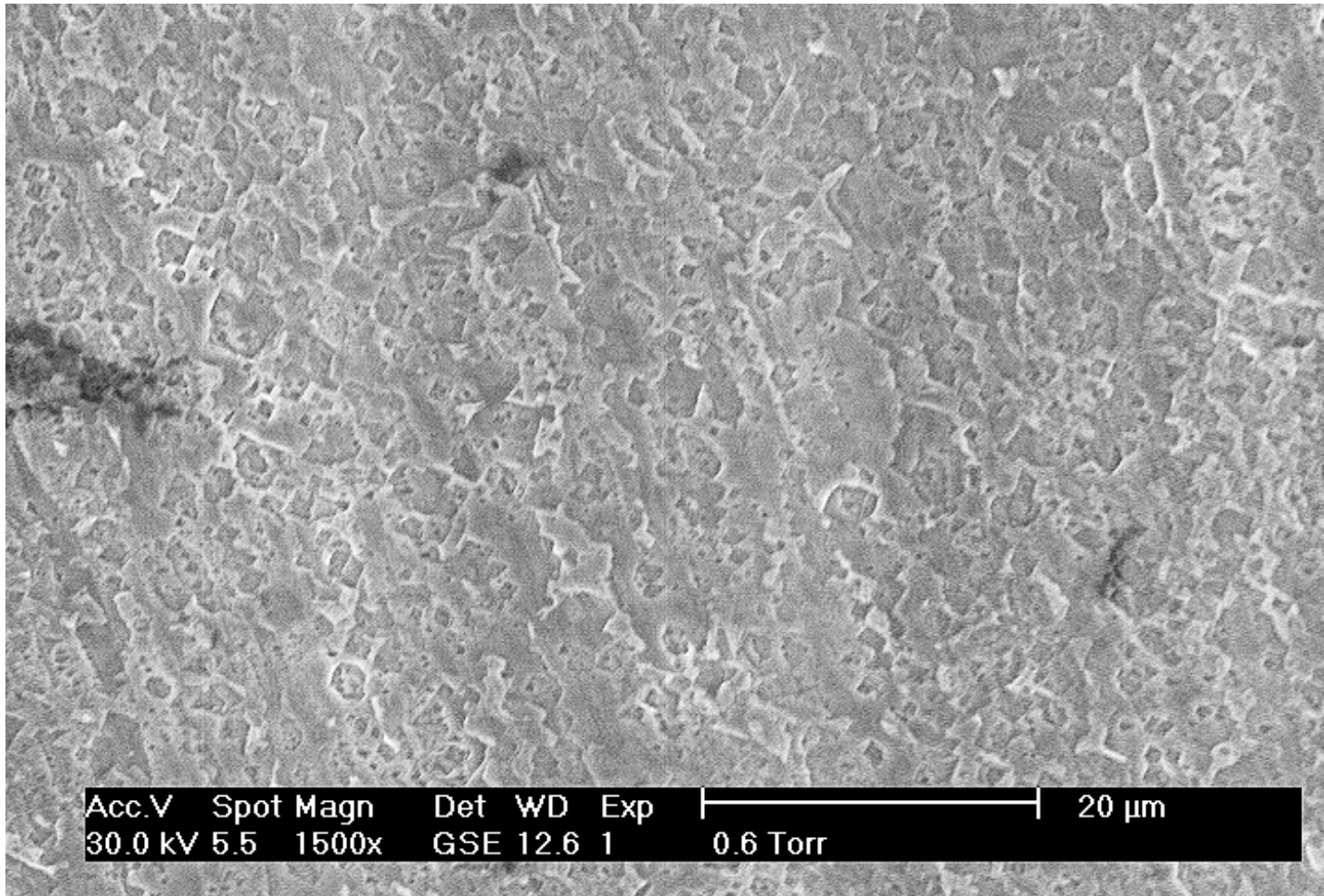
Dynamic studies on oxidation

- W-foil
- *In situ* studies in an ESEM* using a hot stage
- Heated from 25° to 1000°C
- Atmosphere of water vapour at low pressure (~100Pa)

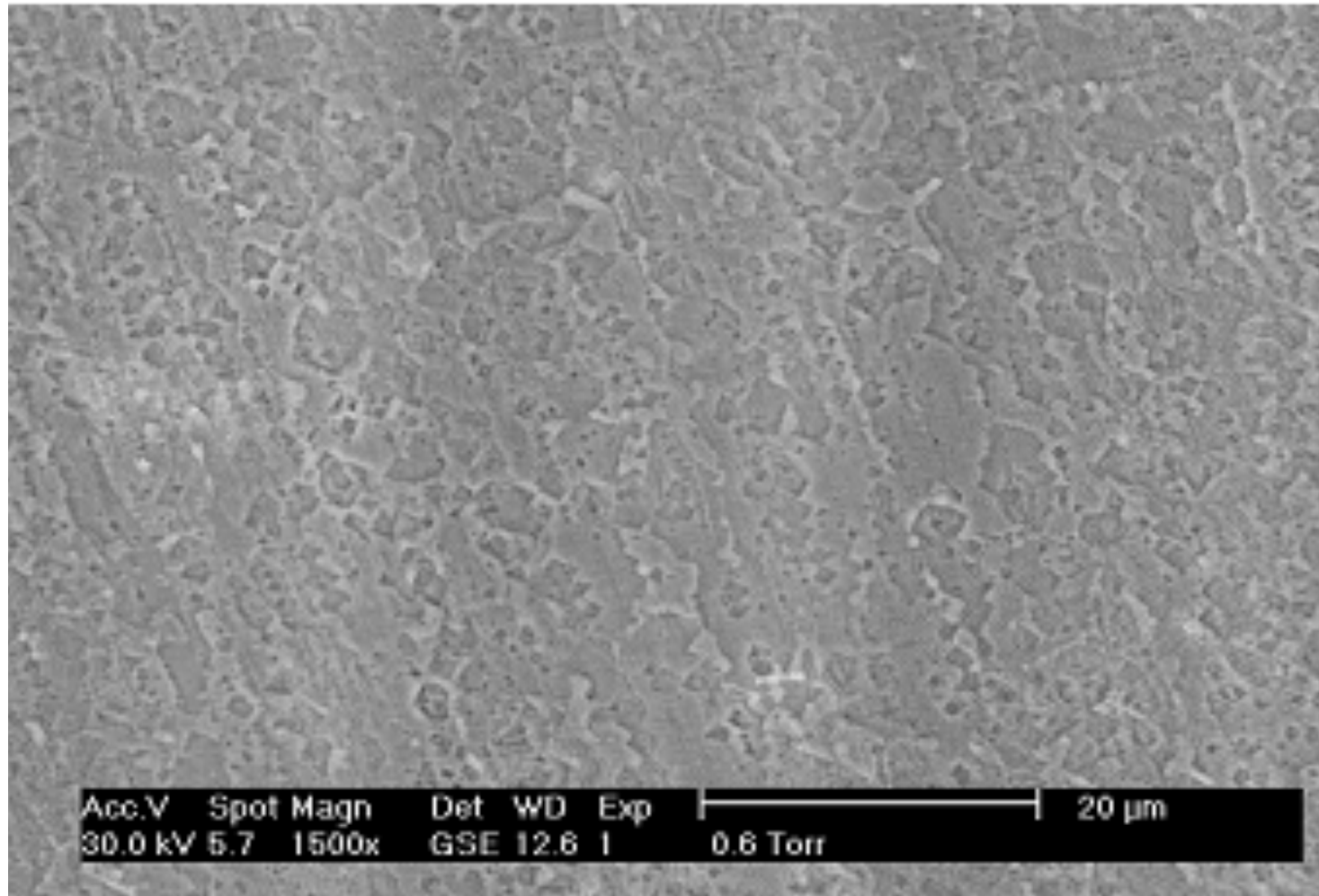
**Environmental Scanning
Electron Microscope*



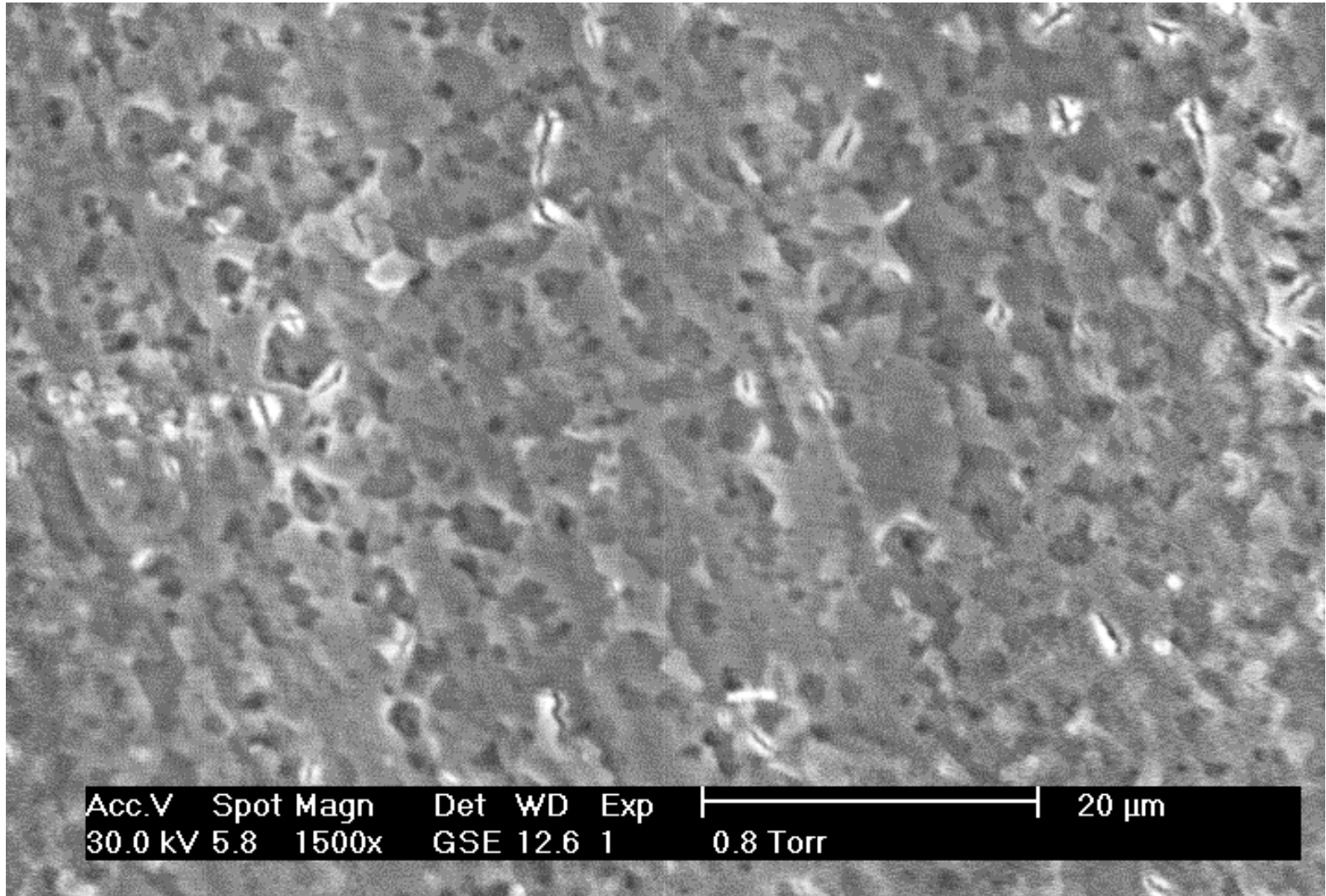
W-foil surface at 25°C



W-foil Surface at 605°C

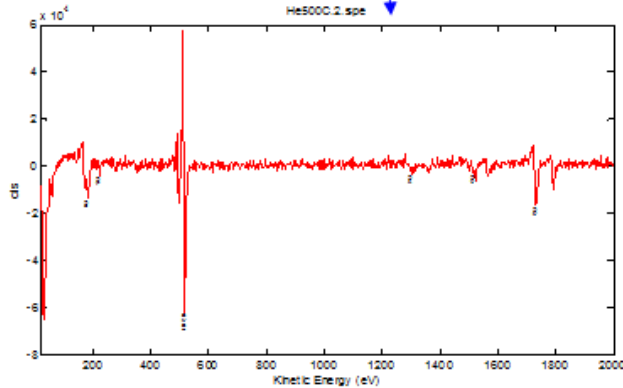
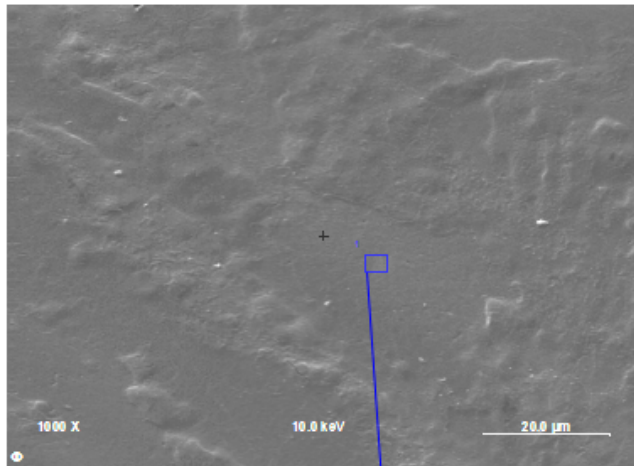


W-foil surface at 700°C

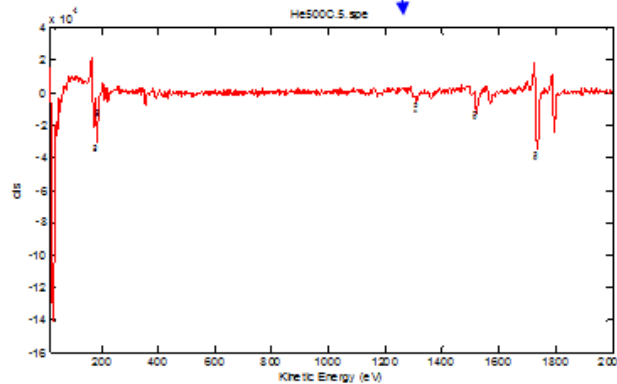
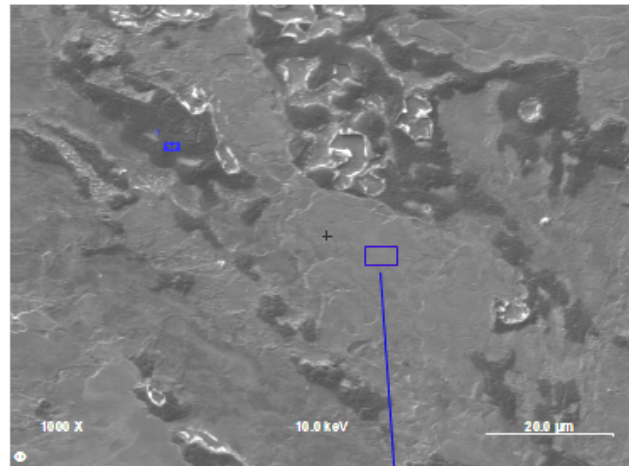


AES of (500°C, He, 2h)-sample

Before sputtering

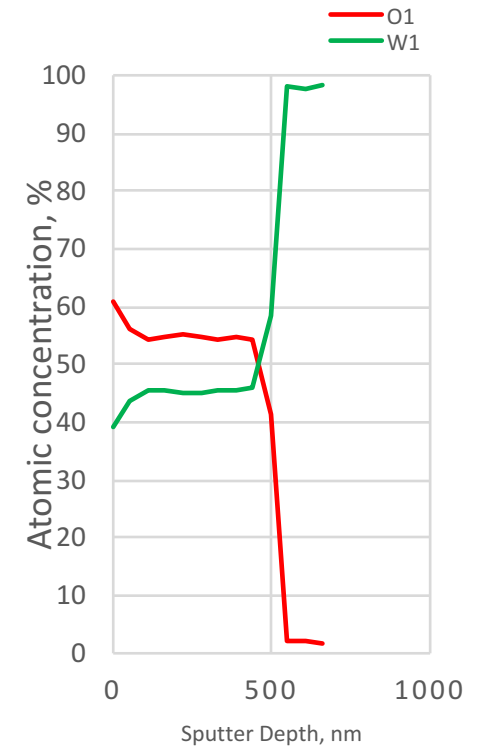


After 12 min sputtering



The survey spectrums before and after sputtering

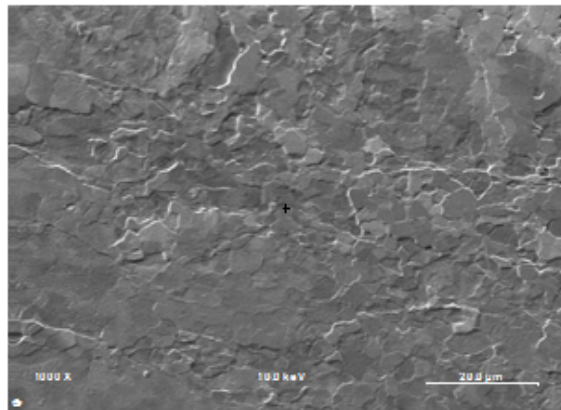
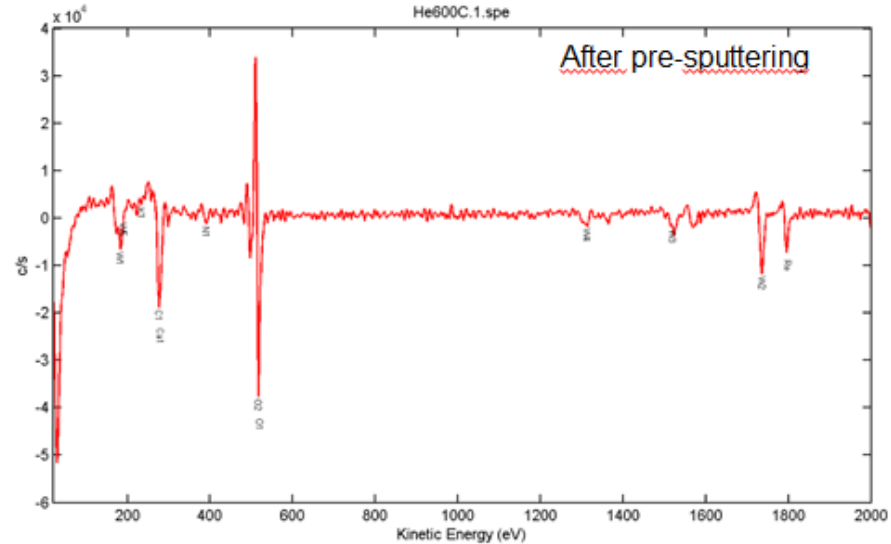
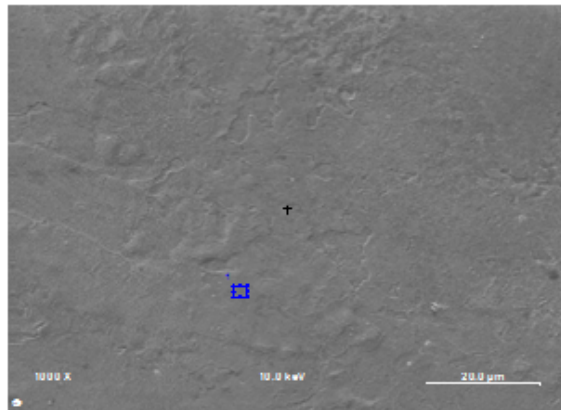
He 500C



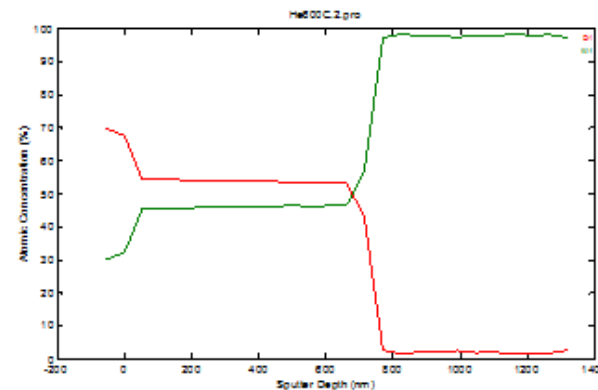
Oxide layer
thickness ~550 nm

AES of (600°C, He, 2h)-sample

AES: survey & depth profile



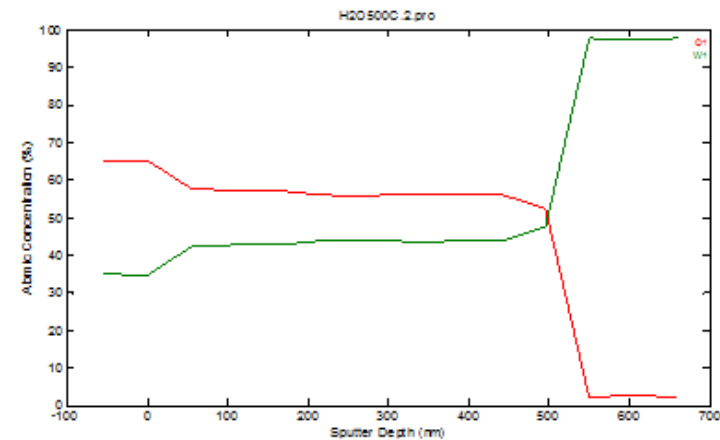
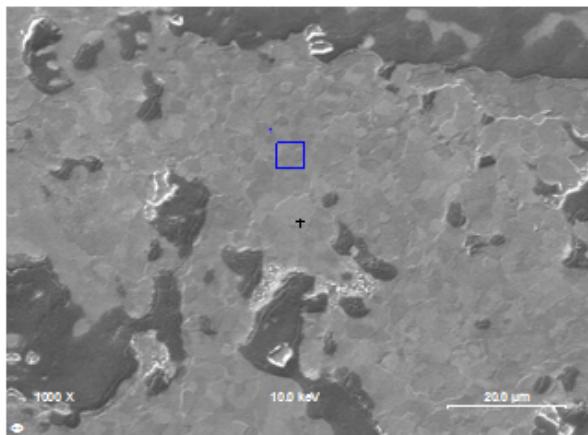
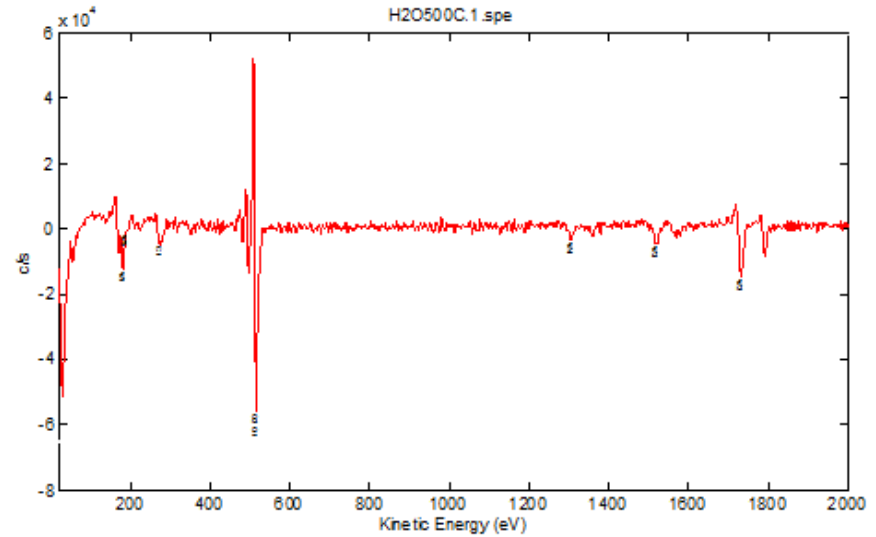
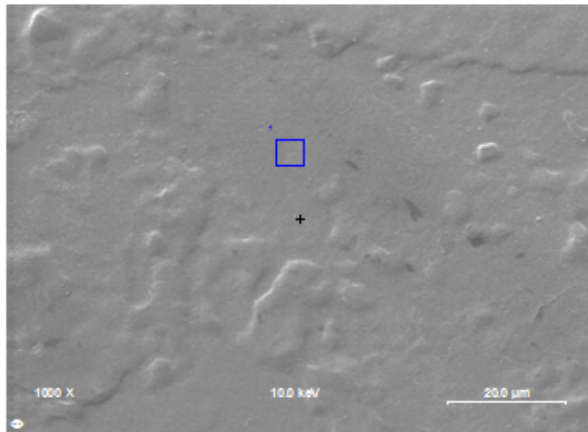
After 24 min sputtering



Oxide layer
thickness:
~770 nm

AES: He+Ar+H₂O, 500C, 2h

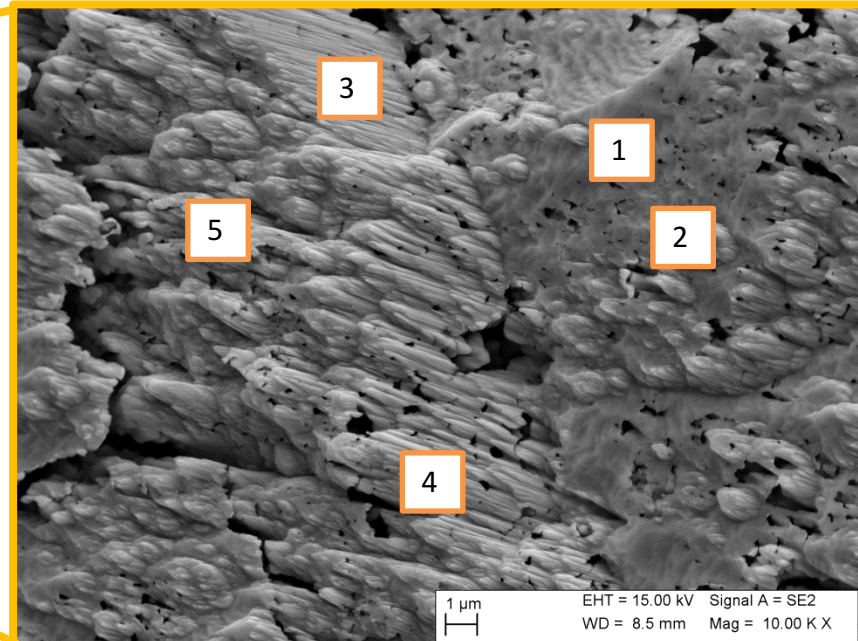
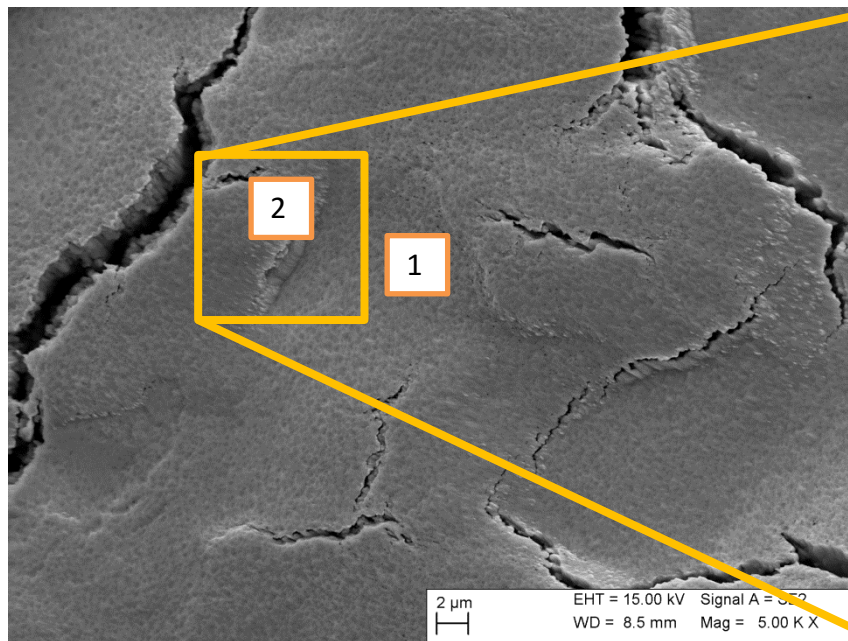
AES: survey & depth profile



After 12 min sputtering

Oxide layer thickness: ~550 nm

EDS+SEM on (700°C, He+Ar+H₂O, 2h)-sample



Position	at. % O	at. % W	O/W
1	71.96	28.04	2.57
2	66.58	33.42	1.99

Position	at. % O	at. % W	O/W
1	73.06	26.94	2.71
2	67.23	32.77	2.05
3	75.36	24.64	3.06
4	70.24	29.76	2.36
5	71.75	28.25	2.54

- Oxidation behaviour of pure W has been studied
 - Methods: Thermogravimetry, TG/STA/DSC, In situ Microscopy. Isothermal & non-isothermal studies. XRD, EDS, AES. Temp: 400-1075°C
- Oxidation environment
 - He+5%O₂, He+0.5%O₂, He+5ppmO₂, H₂O(g), Ar/He, Ar+He+H₂O, Air
- Lower oxides of W are formed during the initial stages of oxidation and are stable at relatively low temperatures and partial pressures of oxygen
- Oxides formed below 600°C are dark, adhesive and protective. Oxide layers formed at higher temperatures are porous and non-protective.
- Water vapor oxidizes tungsten less than oxygen, but contributes to the sublimation of WO₃.

Summary cont.

- Oxidation is parabolic initially, tending to be linear at higher T and for longer oxidation (48h). At low T, W shows oxidation tendencies even at low oxygen levels.
- Activation energy for He+0.5%O₂ (95 kJ/mol) is lower than for He+Ar+H₂O (183kJ/mol)
- Activation energy for He-5%O₂ above 700°C (127 kJ/mol) agrees well with the diffusion of oxygen ions in WO₃.
- Sublimation is not significant below 1075°C
- The results indicate that oxidation occurs in inert gases containing oxygen impurity (max. 5ppm O₂)